

FORM PTO-1449
(Rev. 7-80)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

Atty. Docket No. 14657

Serial No.
10/811,153

LIST OF PRIOR ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT Lu

FILING DATE 3/29/04

GROUP 1774

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
CF	AA	US 2002 0093006A1	7/18/02	Vardeny et al.			
	AB	US 2003 0042846A1	3/6/03	Forrest et al.			
	AC	4356429	10/26/82	Tang			
	AD	5171373	12/15/92	Hebard et al.			
	AE	5759725	6/2/98	Hirao et al.			
	AF	5776622	7/7/98	Hung et al.			
	AG	5861219	1/19/99	Thompson et al.			
	AH	6310360	10/30/01	Forrest et al.			
	AI	6486601	11/26/02	Sakai et al.			
	AJ	6515298	2/4/03	Forrest et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
CF	AK	WO 02 058110 A2	7/25/02	International.			X	
	AL	JP 5331458	12/14/93	Japan			abstract in English	
	AM	JP04-144479	1992	Japan			abstract in English	

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

CF	AN	Metal/AlQ ₃ Interface Structures, Turak et al., Applied Physics Letters, Vol. 81, No. 4, 22 July 2002, 766-768
CF	AO	Organic Light-Emitting diodes with a Nanostructured Fullerene Layer at the Interface between AlQ ₃ and TPD Layers, Kato et al., Jpn. J. Appl. Phys. Vol. 42 (2003) pp 2526-2529, Part 1. No. 4B, April 2003

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 602; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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OCT 07 2004

APPLICANT Lu et al.

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	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

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							YES	NO
UF	AL	WO 02/058110 A2 and A3	7/25/2002	International			X	
	AM							
	AN							
	AO							

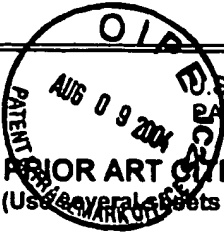
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AP	
	AQ	

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EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
CF	AA	5	8	6	1	2	1	9	01/19/99				
	AB	5	7	5	9	7	2	5	06/02/98				
	AC	5	7	7	6	6	2	2	07/07/98				
	AD	6	5	1	5	2	9	8	02/04/03				
	AE	6	4	8	6	6	0	1	11/26/02				
	AF	6	3	1	0	3	6	0	10/30/01				
	AG	2002/0093006							07/18/02				
	AH	2003/0042846							03/06/03				
	AI	4	3	5	6	4	2	9	10/26/82				
	AJ	5	1	7	1	3	7	3	12/15/92				
	AK												

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	AN													
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CF	AP	"Metal/AlQ ₃ Interface Structures", Turak et al. Applied Physics Letters, July 22, 2002, Vol. 81(4), pp 766-768.
CF	AQ	"Organic Light-Emitting Diodes with a Nanostructured Fullerene Layer at the Interface between Alq ₃ and TPD Layers", Kato et al.; Jpn. J. Appl Phys, April 2003, Vol. 42(2003), pp 2526-2529.

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